

Features

- Very Low On-resistance RDS(ON)
- LowCrss
- Fast switching
- Improved dv/dt capability

Application

- PWM Application Load
- SwitchPower
- Management

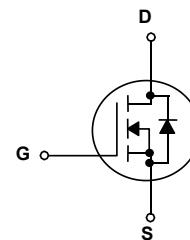
Product Summary



V_{DS}	30	V
$R_{DS(on),Typ} @ V_{GS}=4.5\text{ V}$	21	$\text{m}\Omega$
I_D	5.6	A



SOT-23



Absolute Maximum Ratings

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	ASDM3400AZA	Units
V_{DSS}	Drain-Source Voltage	30	V
I_D	Drain Current - Continuous ($T_C = 25^\circ\text{C}$)	5.6	A
	- Continuous ($T_C = 100^\circ\text{C}$)	3.6	A
I_{DM}	Drain Current - Pulsed (Note 1)	23	A
V_{GSS}	Gate-Source Voltage	± 20	V
P_D	Power Dissipation ($T_C = 25^\circ\text{C}$)	1.4	W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	70	$^\circ\text{C}/\text{W}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

Electrical Characteristics

$T_c = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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Off Characteristics

BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30	--	--	V
$I_{\text{DS}(\text{SS})}$	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 30 \text{ V}, V_{\text{GS}} = 0 \text{ V}$	--	--	1	μA
		$V_{\text{DS}} = 30 \text{ V}, T_c = 55^\circ\text{C}$	--	--	5	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = 12 \text{ V}, V_{\text{DS}} = 0 \text{ V}$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = -12 \text{ V}, V_{\text{DS}} = 0 \text{ V}$	--	--	-100	nA

On Characteristics

$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250 \mu\text{A}$	0.6	-	1.5	V
$R_{\text{DS}(\text{on})}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = 10 \text{ V}, I_D = 5.6 \text{ A}$	--	19	24	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5 \text{ V}, I_D = 5.6 \text{ A}$	-	21	27	
		$V_{\text{GS}} = 2.5 \text{ V}, I_D = 3.0 \text{ A}$	-	27	35	

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{\text{DS}} = 15 \text{ V}, V_{\text{GS}} = 0 \text{ V}, f = 1.0 \text{ MHz}$	--	675	-	pF
C_{oss}	Output Capacitance		--	50	-	pF
C_{rss}	Reverse Transfer Capacitance		--	44	-	pF

Switching Characteristics

$t_{\text{d}(\text{on})}$	Turn-On Delay Time	$V_{\text{GS}} = 10 \text{ V}, V_{\text{DS}} = 15 \text{ V}, R_G = 3 \Omega, R_L = 2.6 \Omega$	--	13	--	ns
t_r	Turn-On Rise Time		--	52	--	ns
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time		--	25	--	ns
t_f	Turn-Off Fall Time		--	10	--	ns
Q_g	Total Gate Charge	$V_{\text{DS}} = 15 \text{ V}, I_D = 5.6 \text{ A}, V_{\text{GS}} = 4.5 \text{ V}$	--	8.6	--	nC
Q_{gs}	Gate-Source Charge		--	1.1	--	nC
Q_{gd}	Gate-Drain Charge		--	2.8	--	nC

Drain-Source Diode Characteristics and Maximum Ratings

I_s	Maximum Continuous Drain-Source Diode Forward Current	--	--	5.6	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	23	A
V_{SD}	Drain to Source Diode Forward Voltage, $V_{\text{GS}} = 0 \text{ V}, I_{\text{SD}} = 5.6 \text{ A}, T_j = 25^\circ\text{C}$	--	0.85	1.2	V

Notes:

- Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
- Device mounted on FR-4 PCB, 1inch x 0.85inch x 0.062 inch
- Pulse Test: Pulse Width≤300μs, Duty Cycle≤0.5%

N- Channel Typical Characteristics

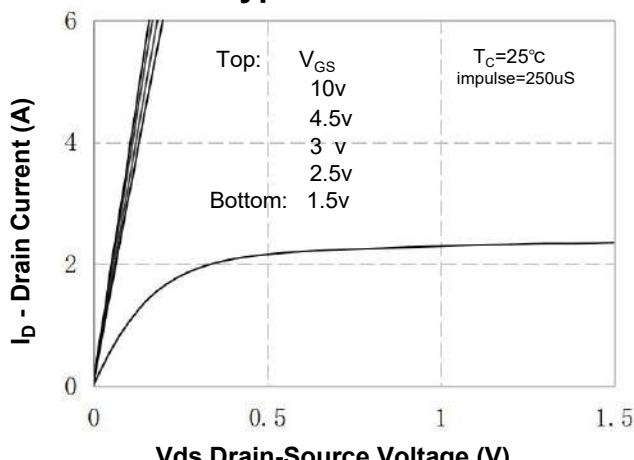


Figure 1. On-Region Characteristics

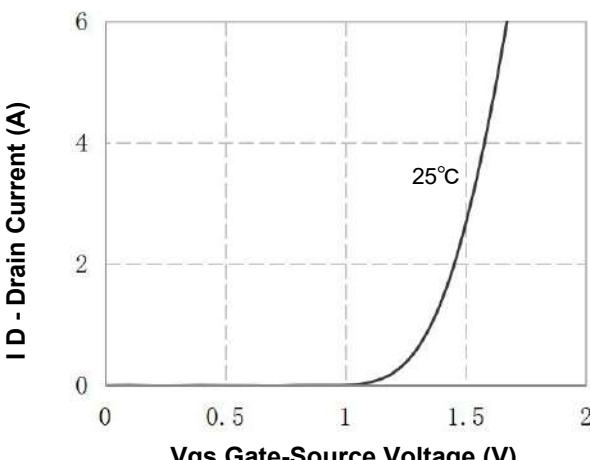


Figure 2. Transfer Characteristics

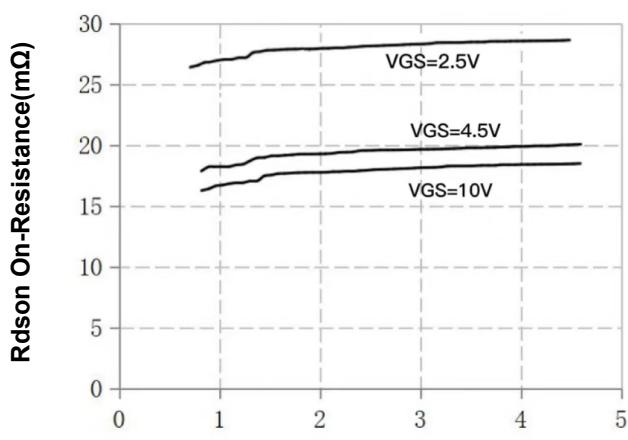


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

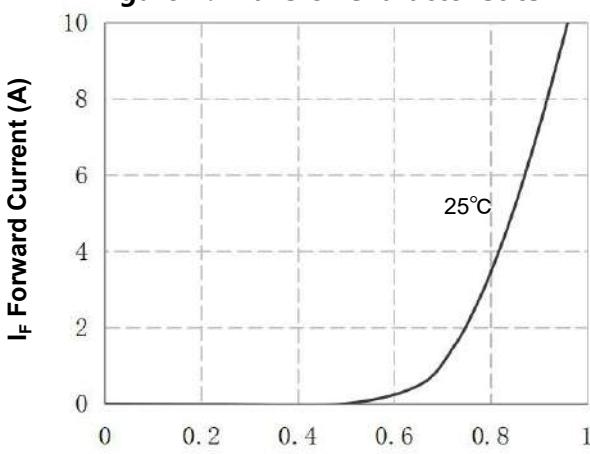


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

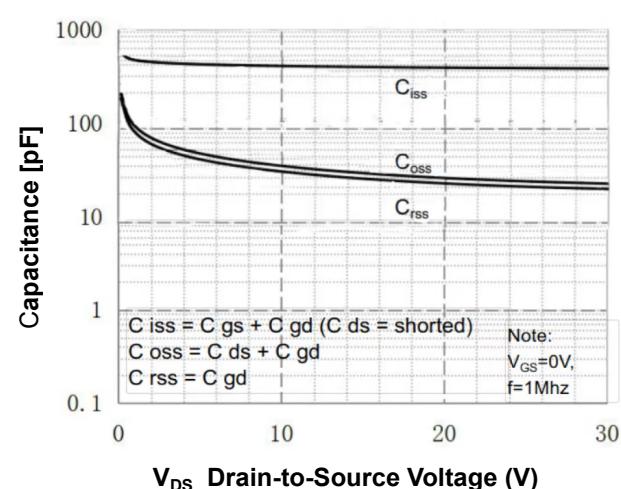


Figure 5. Capacitance Characteristics

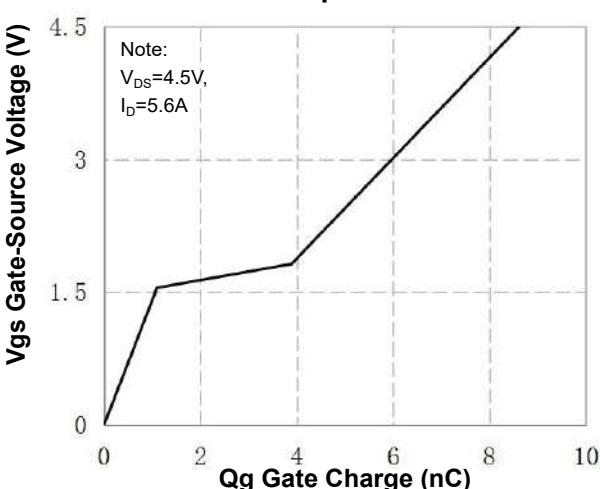
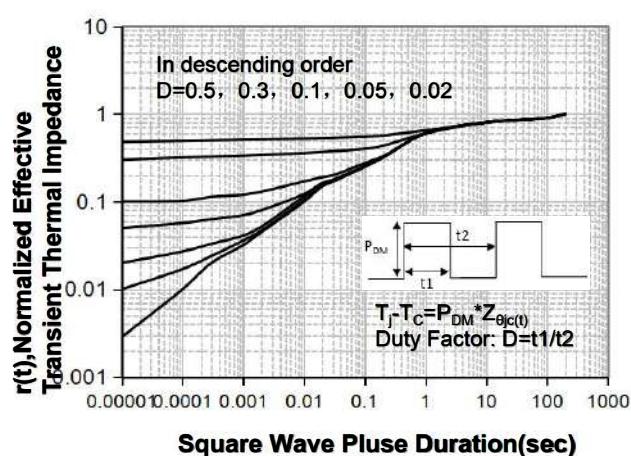
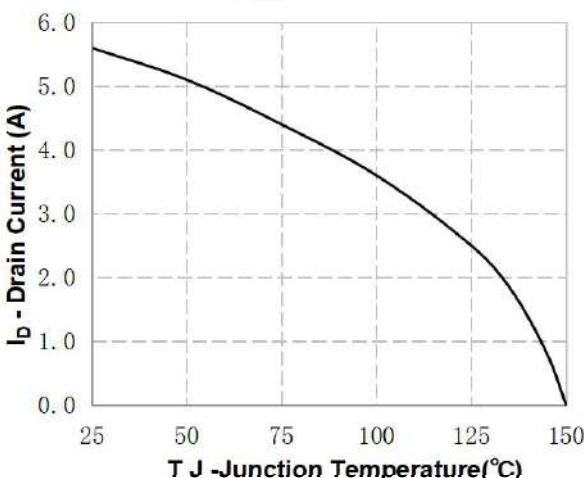
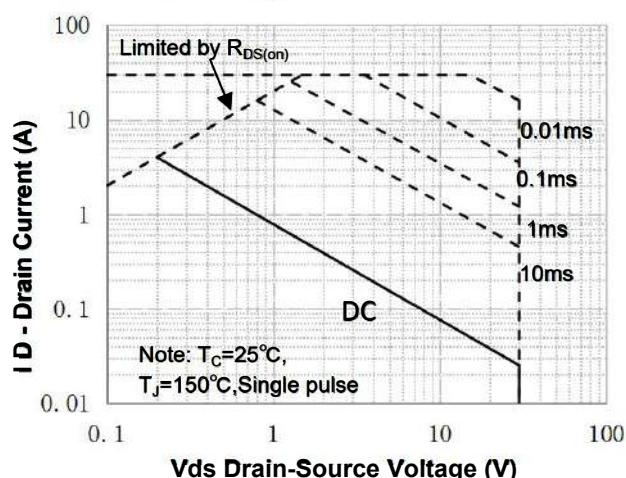
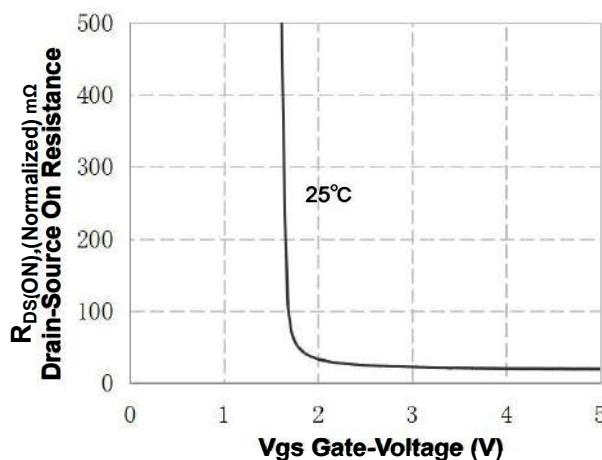
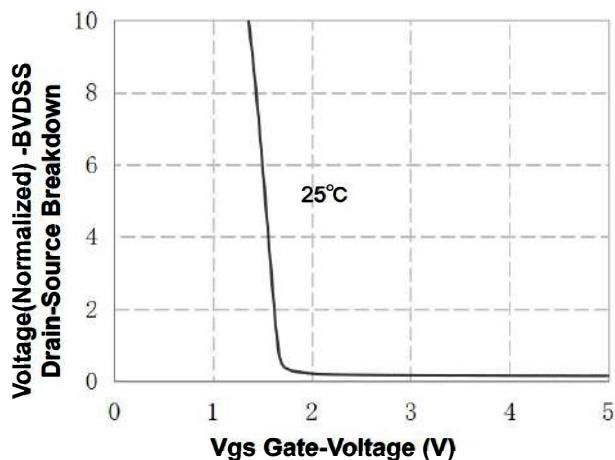
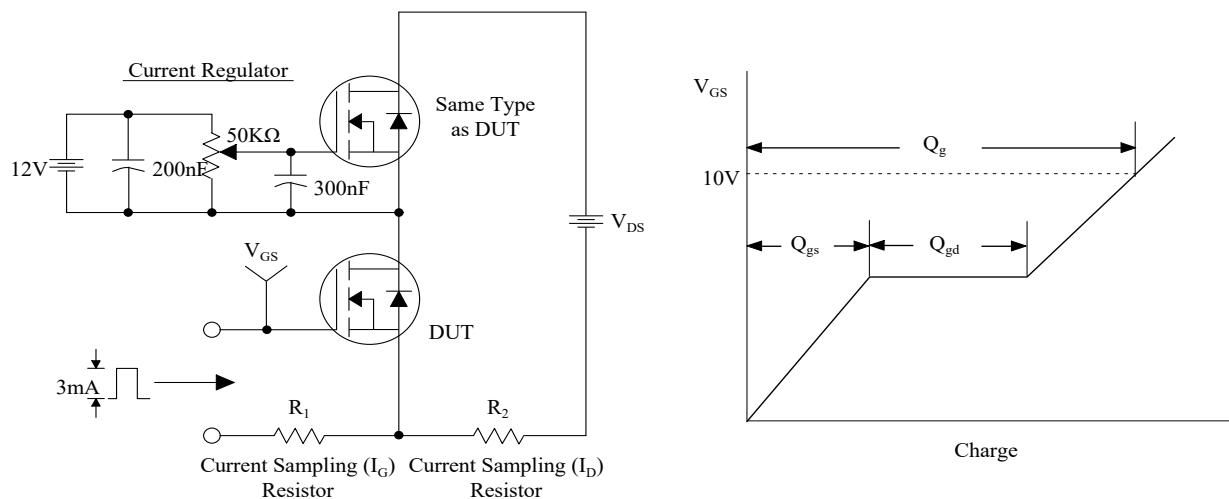


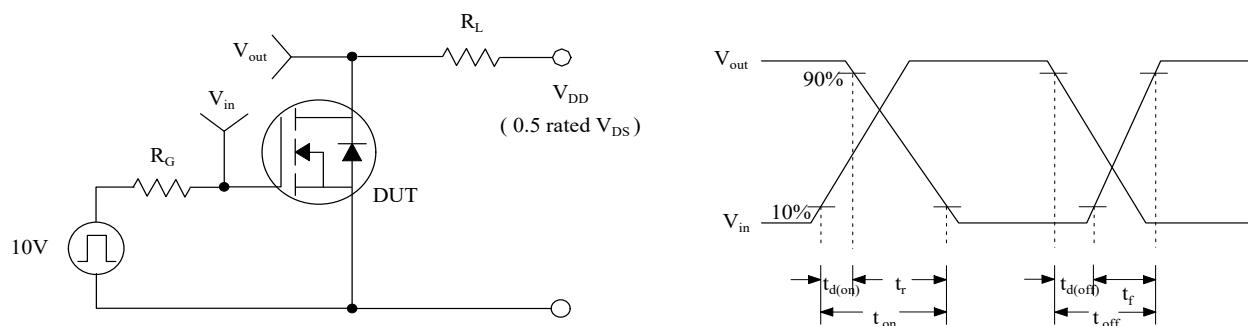
Figure 6. Gate Charge Characteristics

N- Channel Typical Characteristics (Continued)


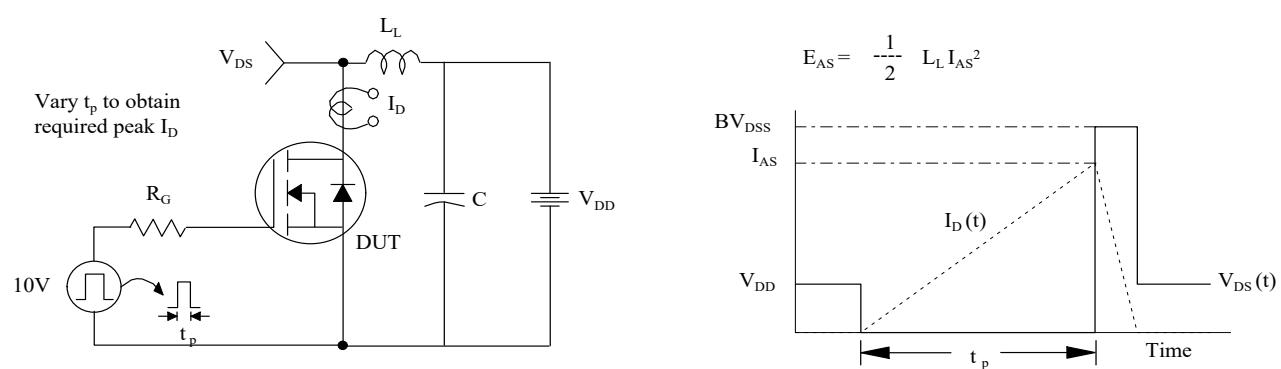
Gate Charge Test Circuit & Waveform



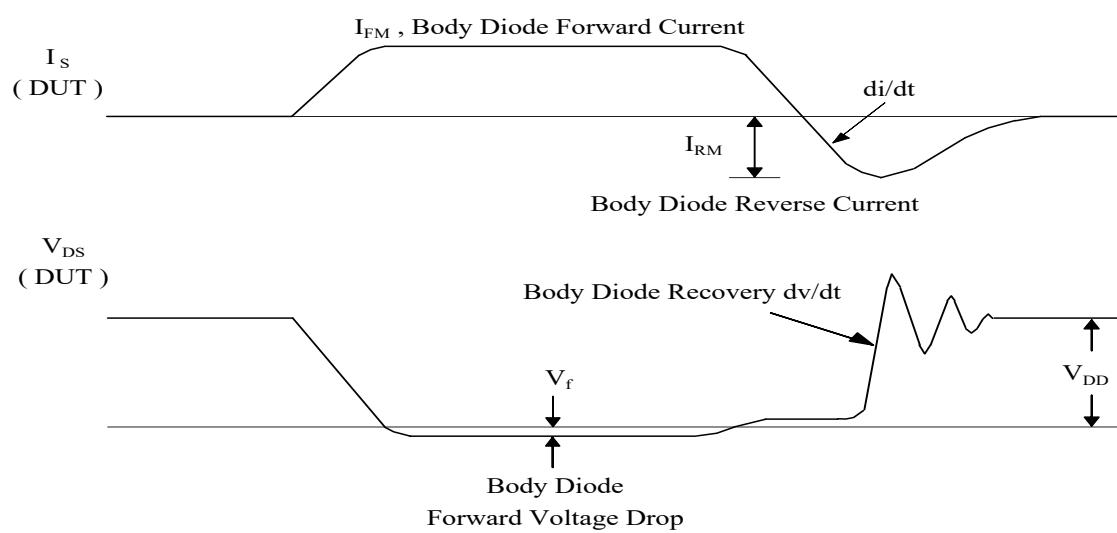
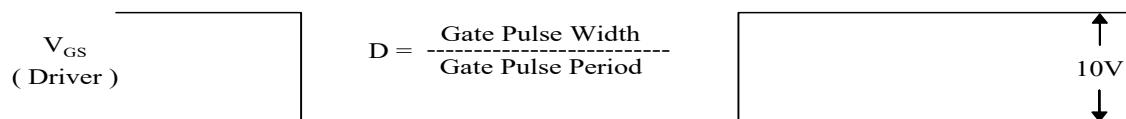
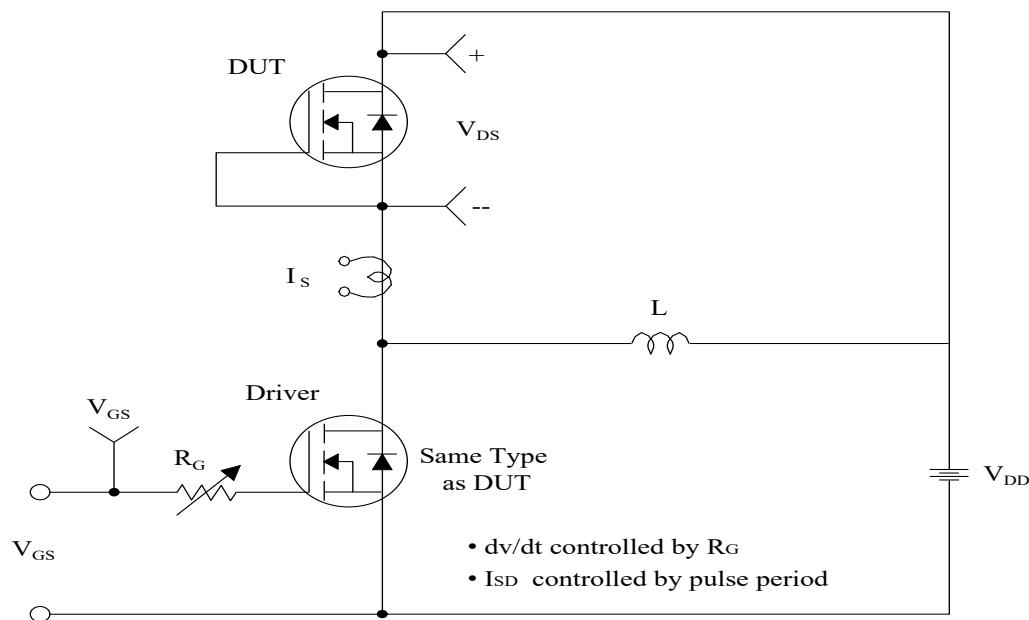
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

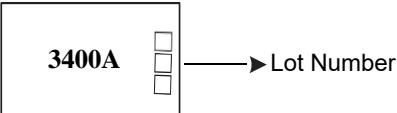


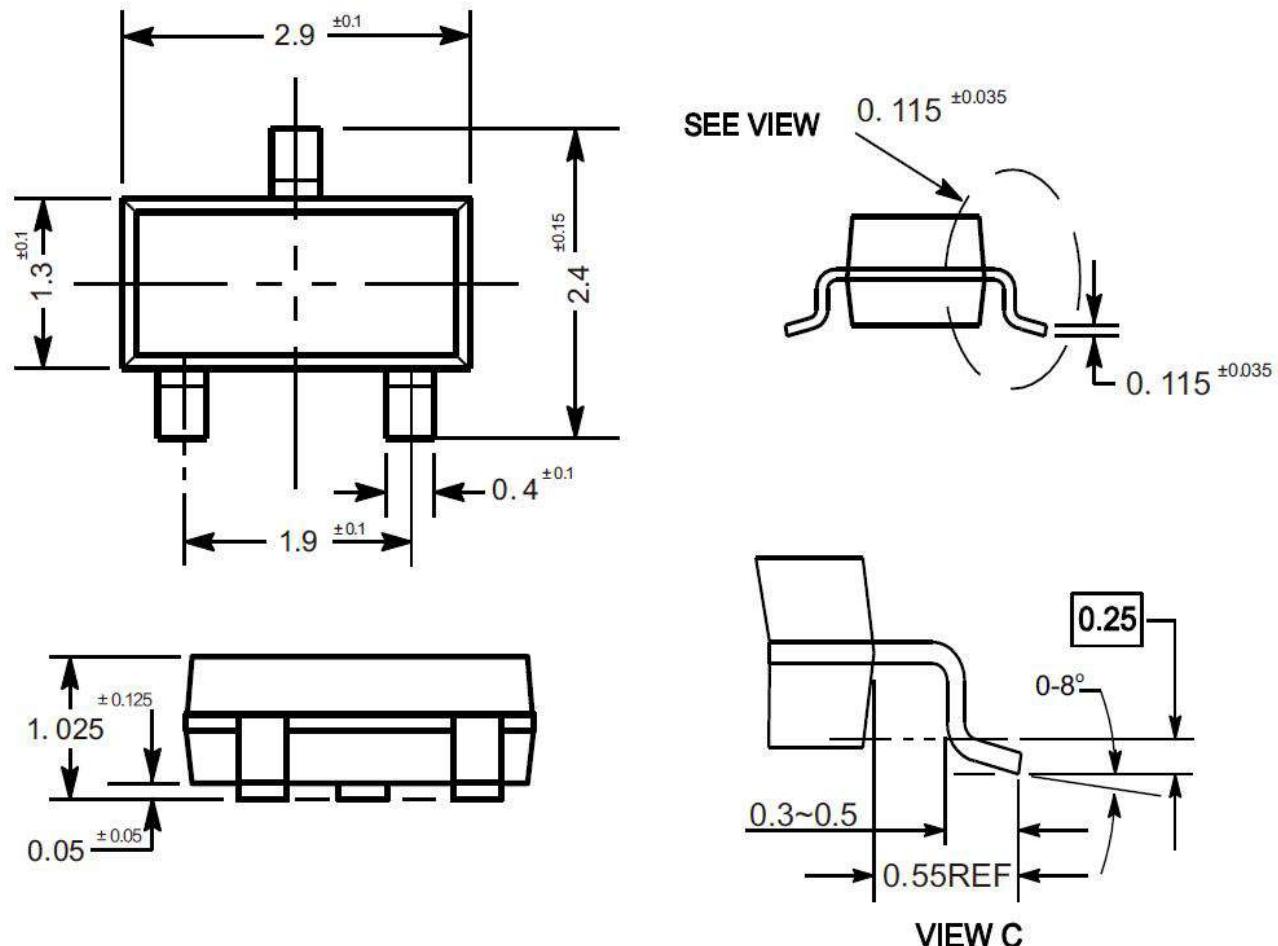
Peak Diode Recovery dv/dt Test Circuit & Waveforms



Ordering and Marking Information

Ordering Device No.	Marking	Package	Packing	Quantity
ASDM3400AZA-R	3400A	SOT-23	Tape&Reel	3000/Reel

PACKAGE	MARKING
SOT-23	



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